

# **SENSOR DEVELOPMENTS (BeamCal)**

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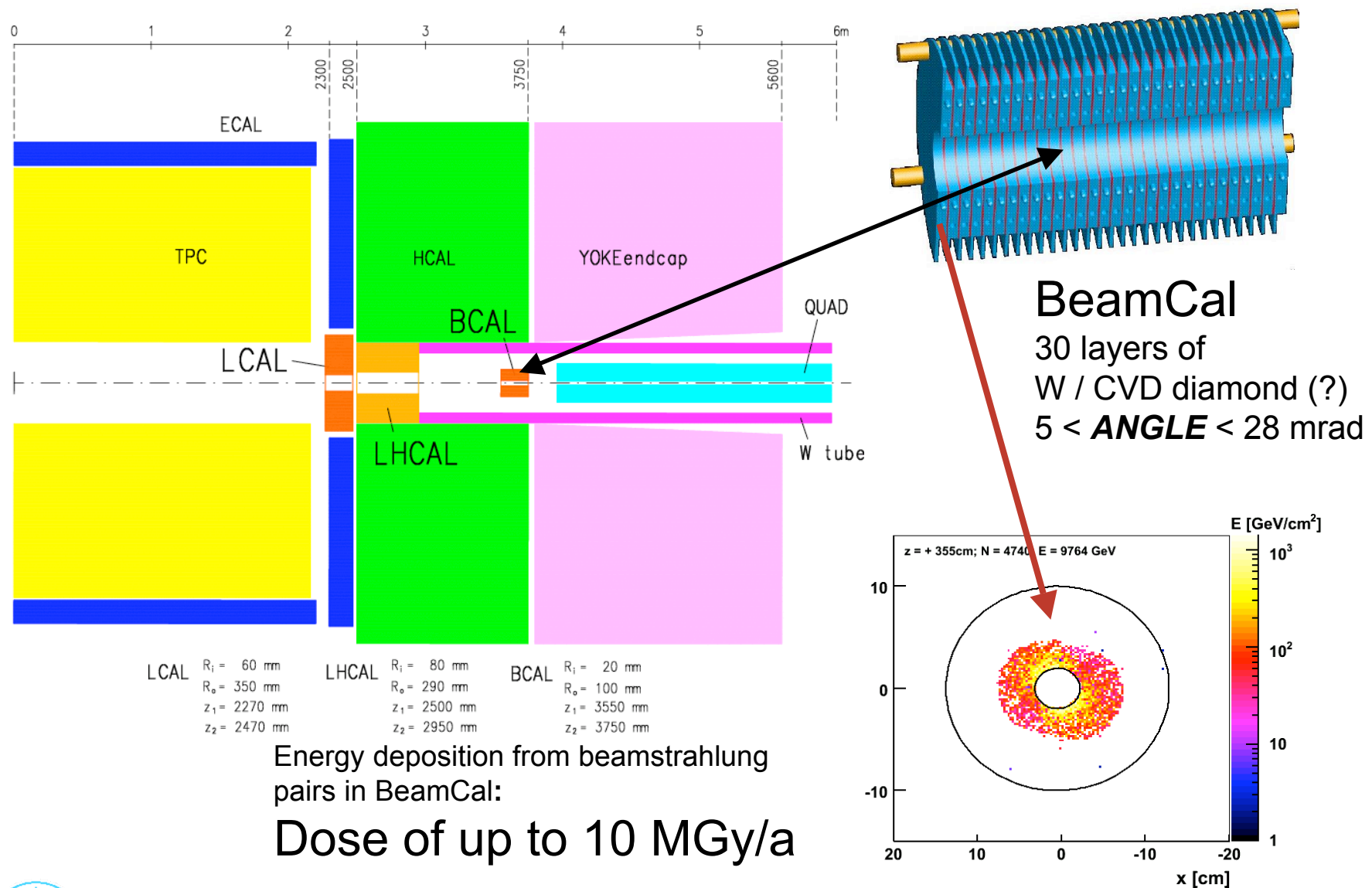


# OUTLINE OF THIS TALK

1. Introduction
2. Silicon
3. CVD Diamonds
4. Gallium Arsenide
5. Silicon Carbide
6. Conclusions



# INTRODUCTION

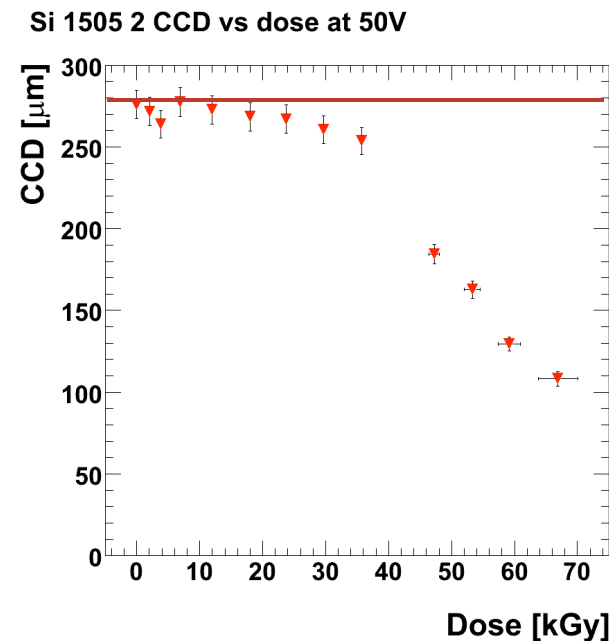


# SILICON (1)

- operated as ‘extended’ pn junction -> depleted intrinsic material (bandgap 1.12 eV)
- The only material which is fully ‘under control’: *reference material*
  - technology: availability, structuring, testing, assembly
  - properties: signal yield, stability, long term behaviour
- Problem: radiation hardness:

*Sample irradiated with  $e^-$ :*  
*Thickness = 280  $\mu\text{m}$*   
*Initial CCD = 280  $\mu\text{m}$*   
*(100% collection efficiency)*

- will improve significantly
- still not sufficient the inner radii of a planned BeamCal





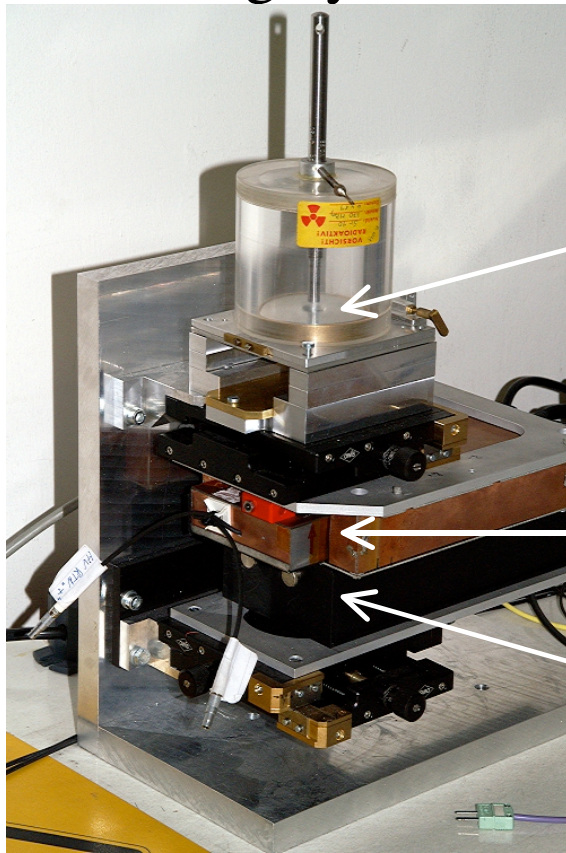
# SILICON (2)

- Problem: radiation hardness:
  - design techniques (instead of p on n --> n in p: avoids type inversion)
  - different growth of substrate material (Czochralsky growth)
  - modification of substrate / doping (oxygenation etc.)
- All these ‘counter measures’ are expensive and time consuming  
--> *joint effort in collaborations!*
- to be investigated: photo diodes with advanced radhard technology
  - samples from Zheng Li (Brookhaven) and Prague  
to be shipped soon, expected for next test beam end of June
  - I/V, C/V, spectra of MIPs
  - irradiation in electron beam planned (S-DALINAC)



# CVD DIAMONDS - polycrystalline (1)

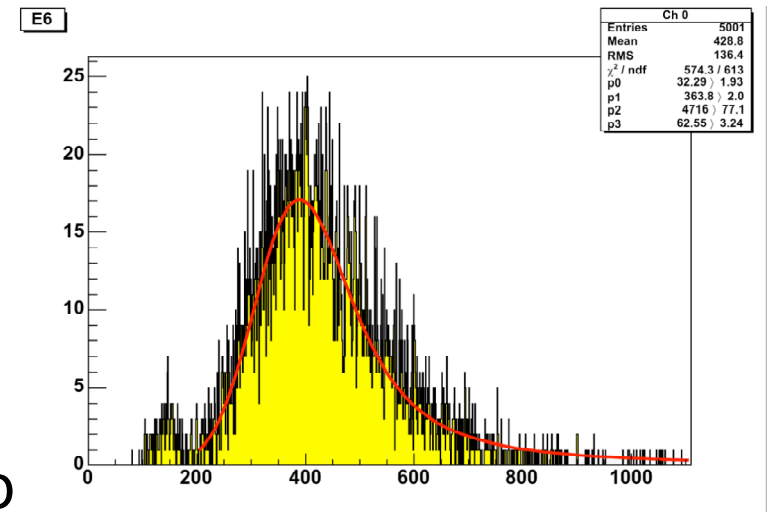
- operated as 'solid state ionization chamber' (bandgap  $\sim 5.5$  eV)
- Different sources: IAF (Fraunhofer, Freiburg), E6
- state of the art: 4" wafers, 6" possible  $\rightarrow$  sensor areas  $> 50 \times 50$  mm<sup>2</sup>
- structuring by metallization ('coarse patterns') w/o photolithography



Source (<sup>90</sup>Sr)

Sensor, Preamp

Trigger



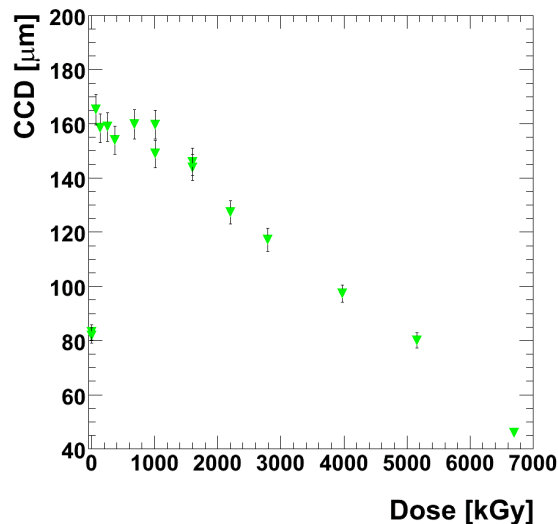
CCE measured:  
(5 to 50)%



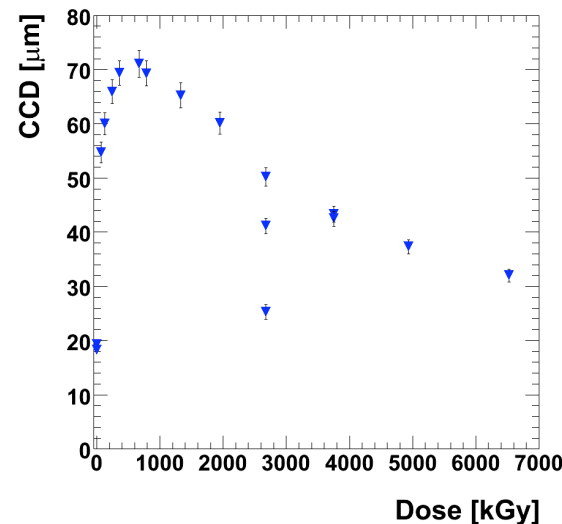
# CVD DIAMONDS - polycrystalline (2)

- radiation hard (survival) but no stable and no predictable behaviour:
  - dependence of CCD on dose acquired (pumping / degradation)

E6\_4p CCD vs dose at 400V



FAP5 CCD vs dose at 400V



- dependence of pumping and degradation on dose rate applied
- changes (vs irradiation) observed: improvement, degradation
- actual properties time dependent (relaxation, recovery)



# CVD DIAMONDS - polycrystalline (3)

- degradation of E6 and of FAP diamonds similar
- investigations of different samples with Raman spectroscopy:
  - significant lower N<sub>2</sub> content of E6
  - no clear correlation to CCD and rad hardness
  - methods to be improved
- annealing with TLC cycles observed (-> traps)
- annealing with UV observed (-> traps)

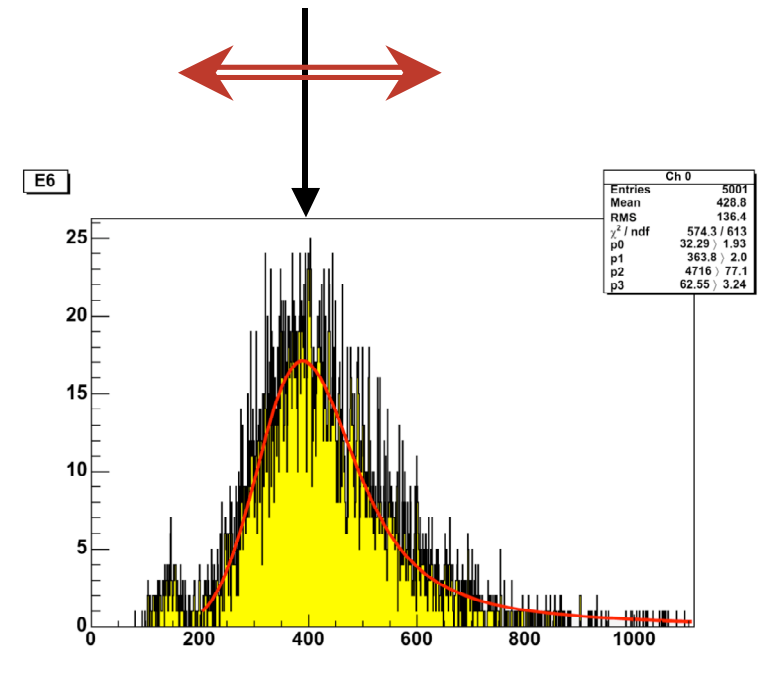


# CVD DIAMONDS - polycrystalline (4)

- signal yield depends on
  - material (sample)
  - conditioning (history, pumping, dose acquired)
  - actual conditions (dose rate)
- applications w/o threshold:
  - spectrometry
  - *instant recalibration necessary*

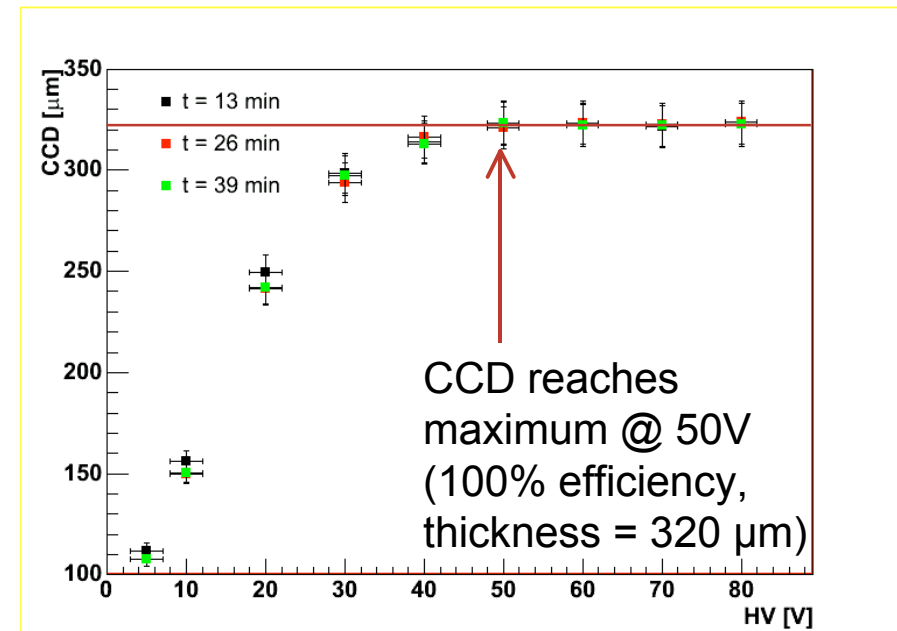
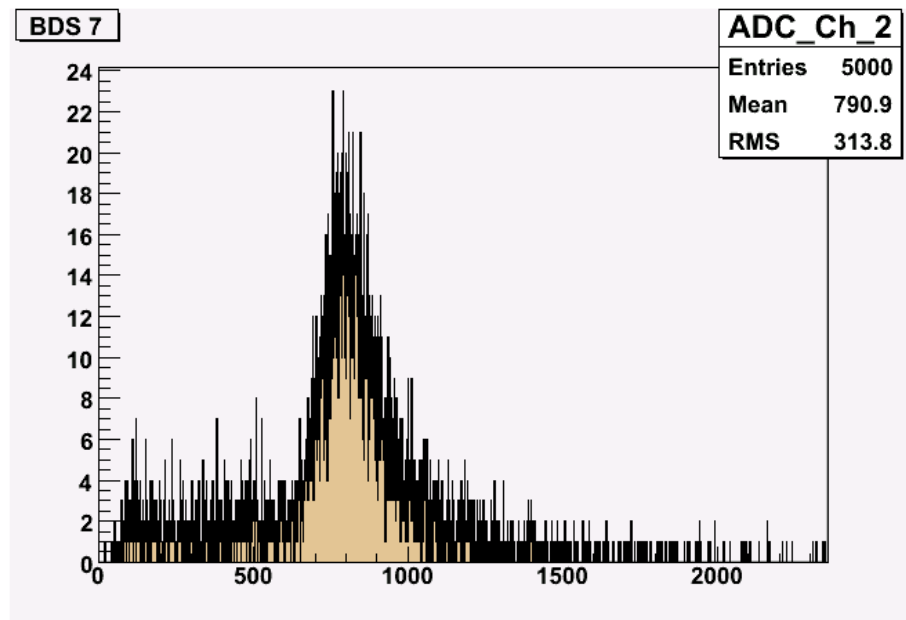


- applications with thresholds  
counting



# CVD DIAMONDS - single crystals (1)

- Single Crystal (CVD grown on substrate) by E6
- Size: 5 x 5 mm<sup>2</sup>, metallization 3 mm in diameter, 320  $\mu\text{m}$  thick

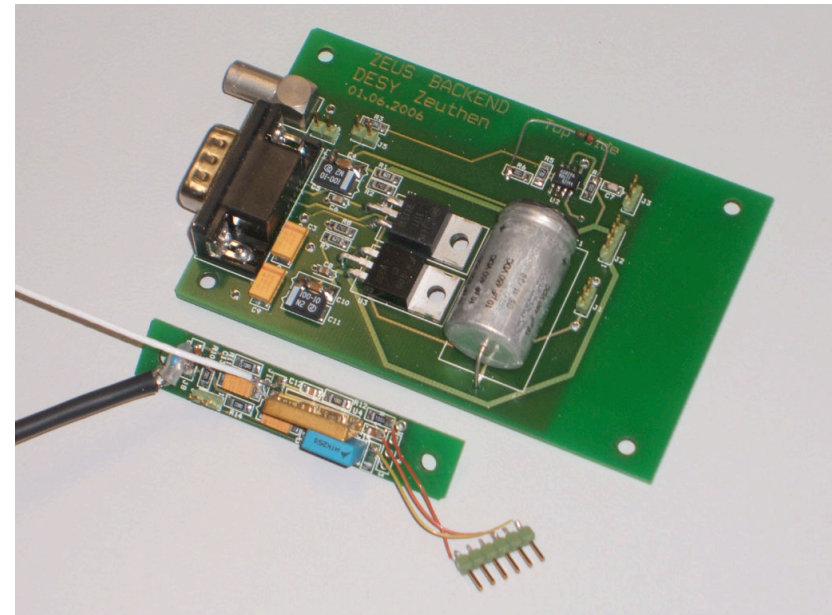
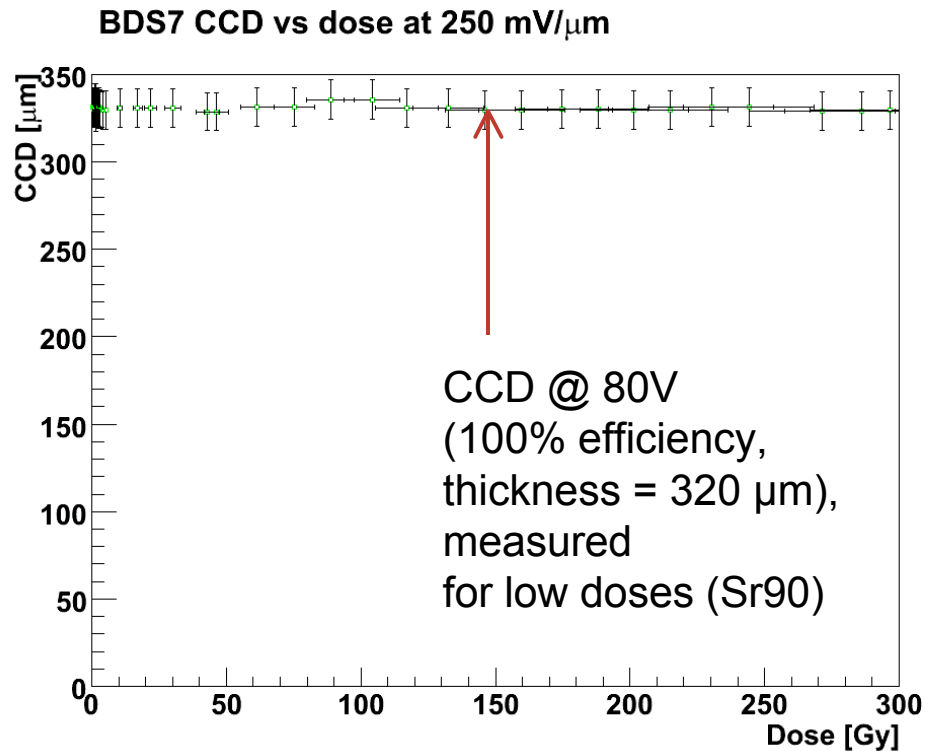


- Clearly separated spectrum of minimal ionizing particles
- 100% CCE, CCD = thickness, 1 mip results in 11.5 ke<sup>-</sup> (1.84 fC)



# CVD DIAMONDS - single crystals (2)

- Stable for low doses ( $< 1\text{kGy}$ ), higher doses not yet known



# CVD DIAMONDS - single crystals (3)

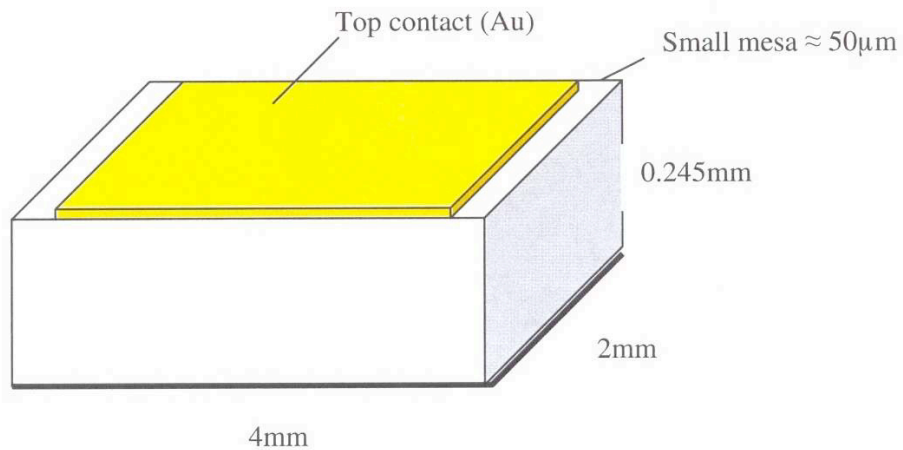
- Installed in ZEUS (HERA, DESY Hamburg)  
close to interaction point (  $\sim 3\text{m}$  )
- Used as a beam background monitor / counter
- Signals fed into DAQ (histogramming)
- Clear Correlation to beam currents (both: electrons, protons)  
(see talk of Alexandre Ignatienko)





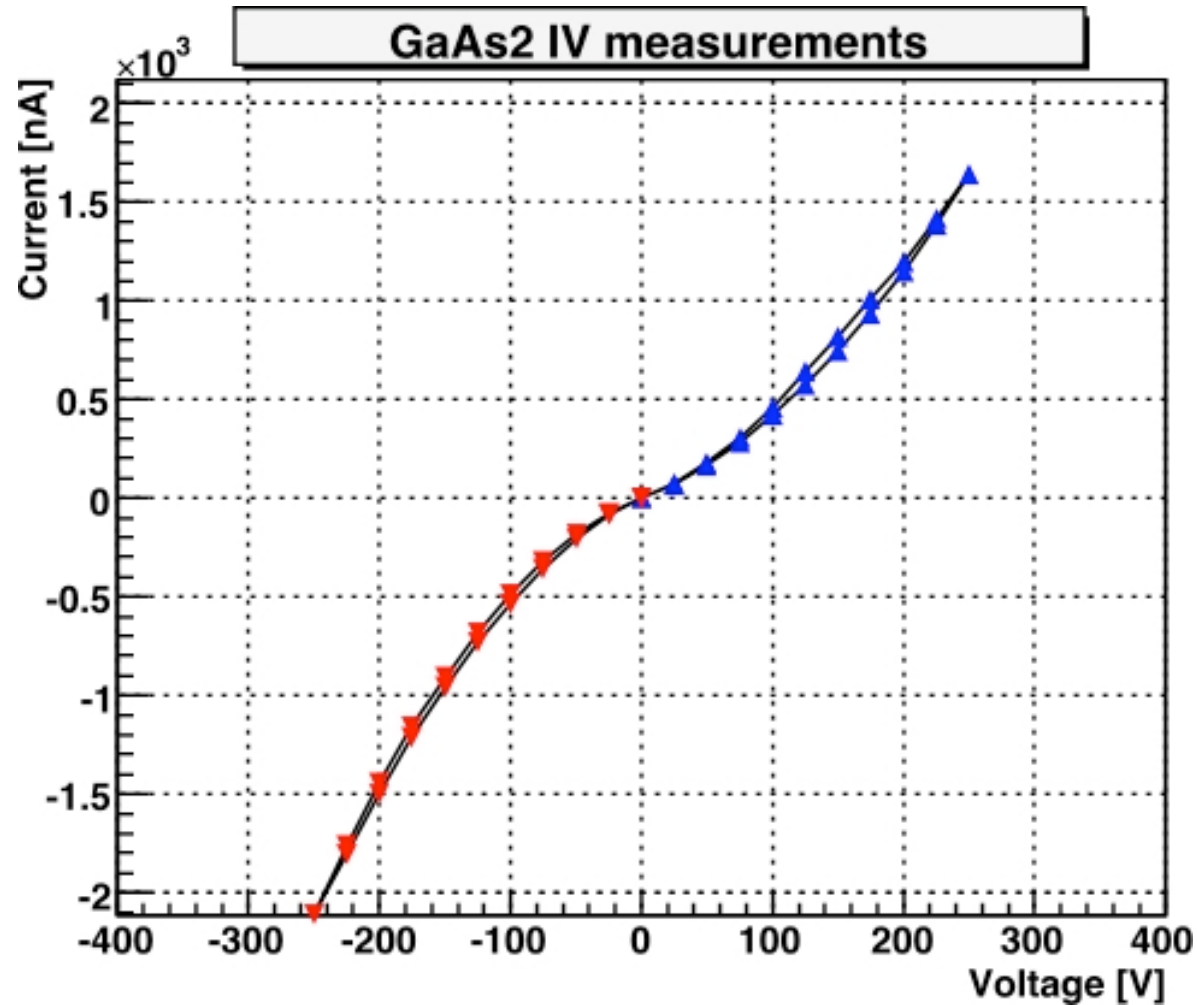
# Gallium Arsenide (1)

- operated as
  - ‘solid state ionization chamber’ (bandgap: 1.42 eV) or as
  - ‘extended pn junction’: p-i-n structure



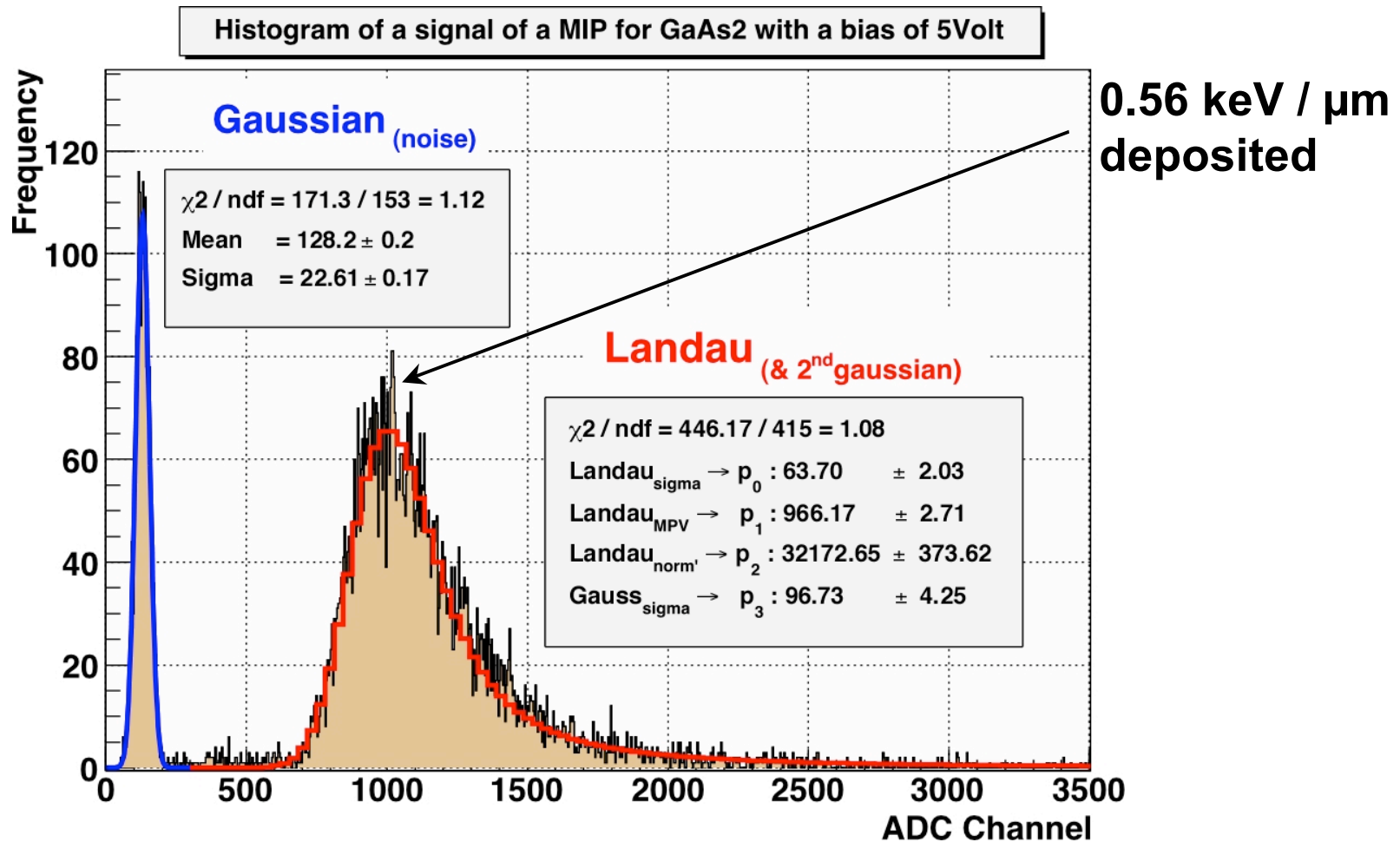
# Gallium Arsenide (2)

- static measurements (I/V)



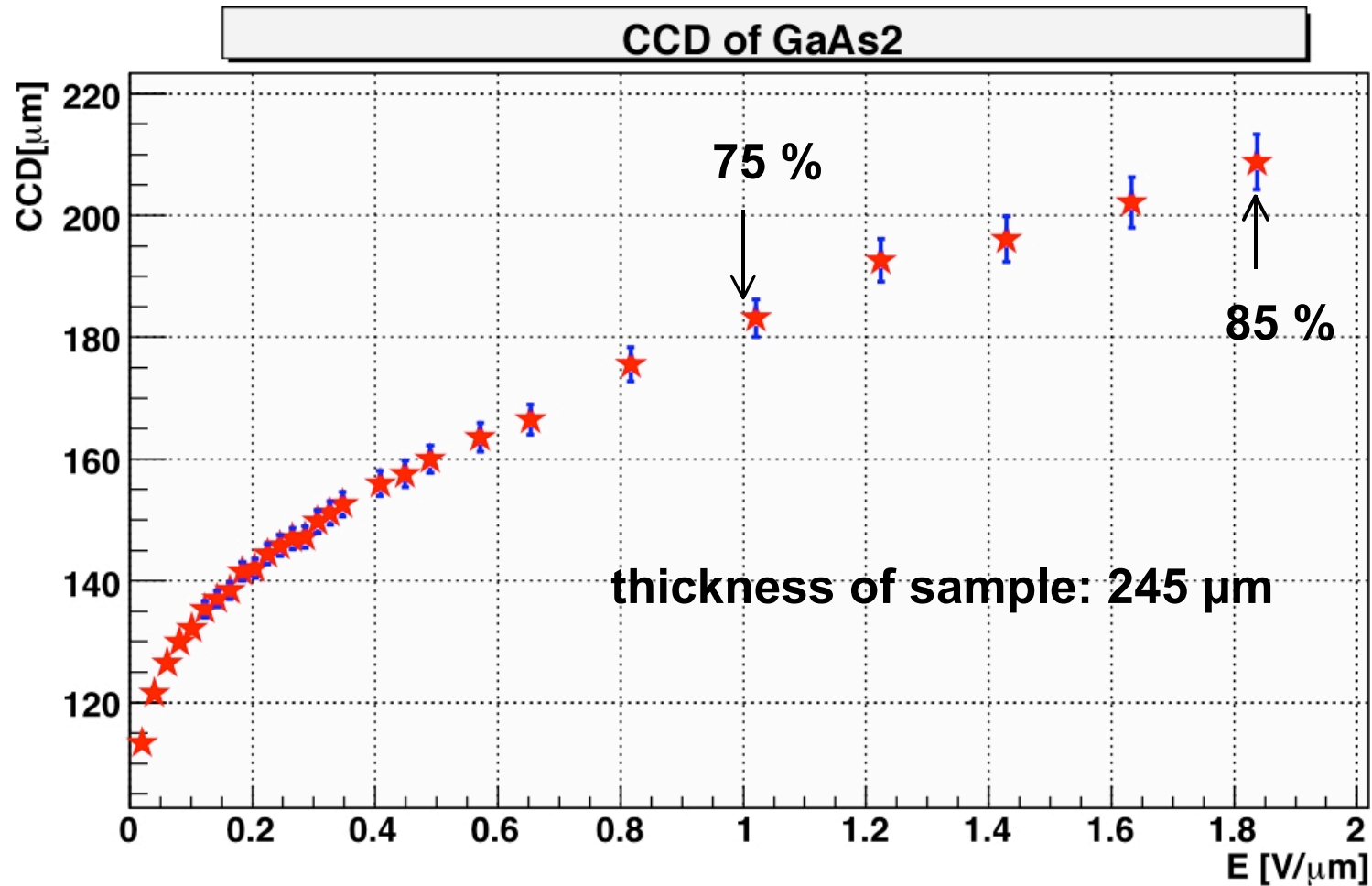
# Gallium Arsenide (3)

- Spectroscopic measurements (Sr 90)



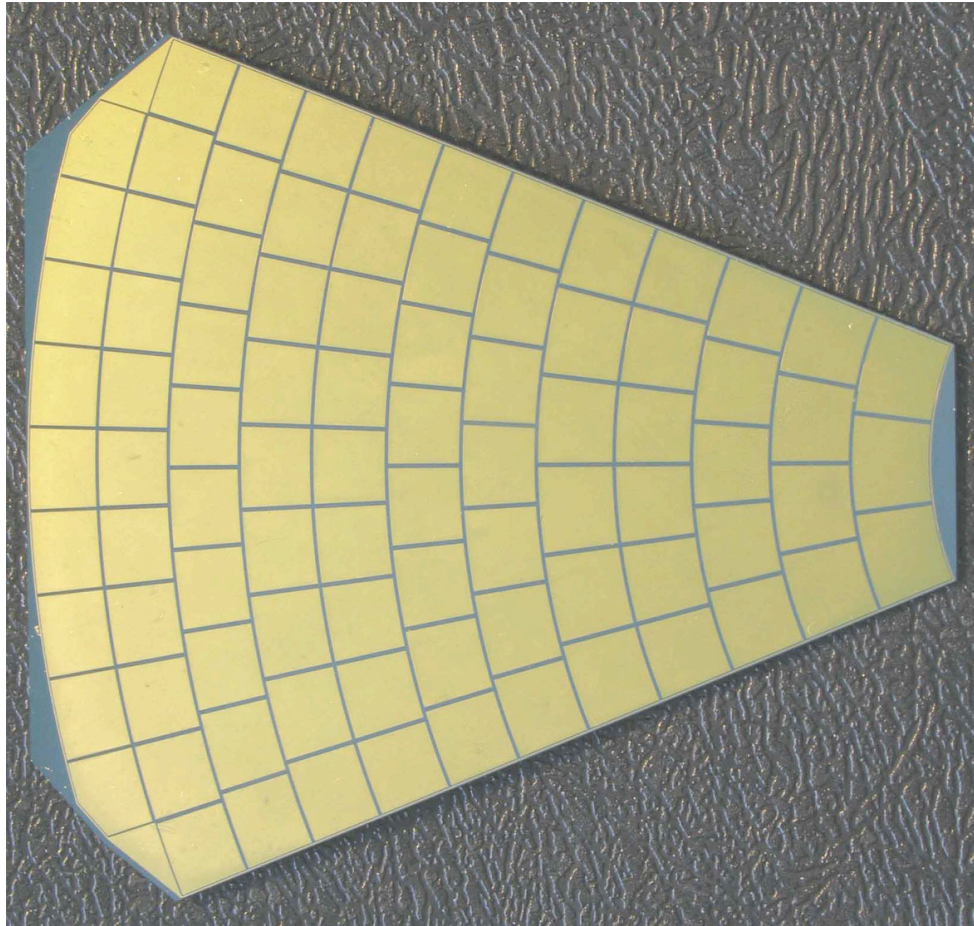
# Gallium Arsenide (4)

- Spectroscopic measurements ( $^{90}\text{Sr}$ ) vs. voltage  $\rightarrow$  CCD



# Gallium Arsenide (5)

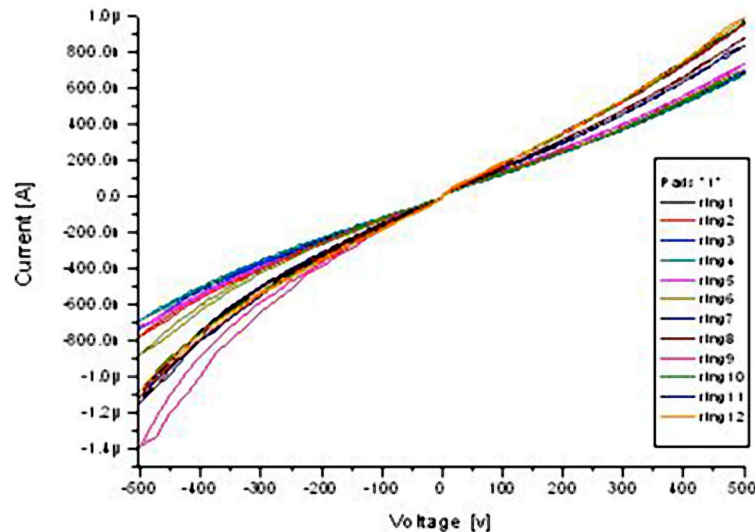
- first detector sample with BeamCal geometry (Dubna / Tomsk)
- compensated (Cr doped) -> behaving as insulator





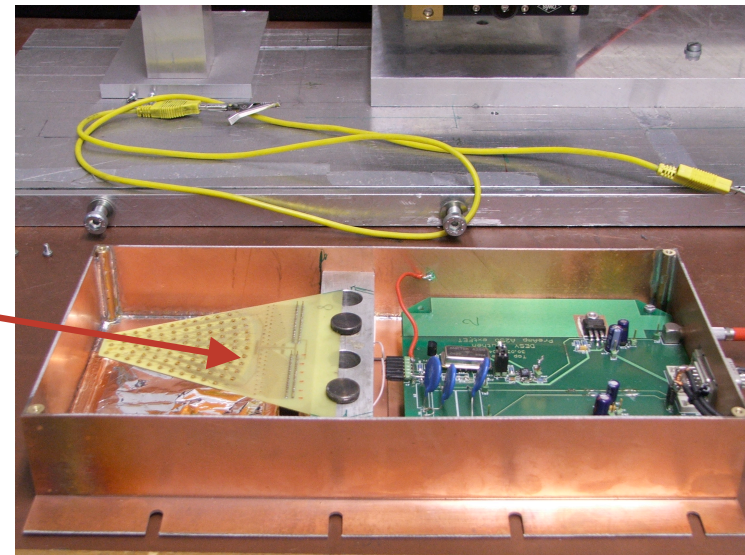
# Gallium Arsenide (6)

- static measurements (I/V)



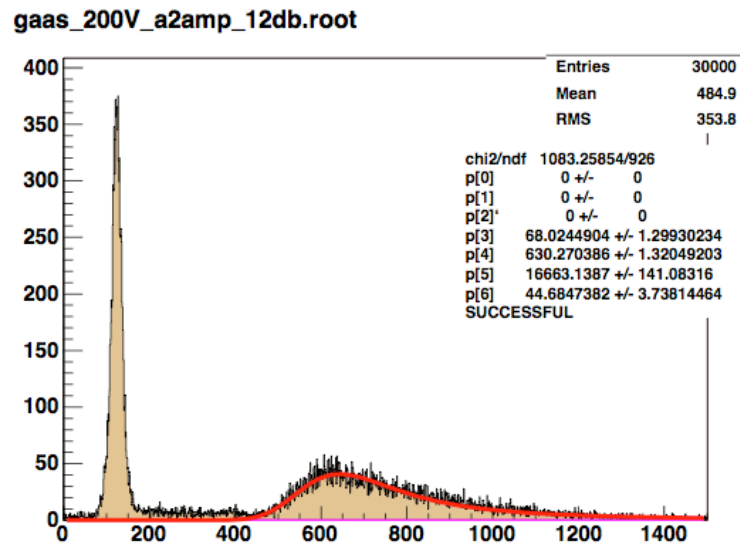
Typical I/V curve for  
different radii  
(power dissipation up to  
 $\sim 0.5$  mW per pad!)  
<-->  $\sim 60$  mW per sensor

Mounting of sensor  
into our test box to  
be measured with  $^{90}\text{Sr}$



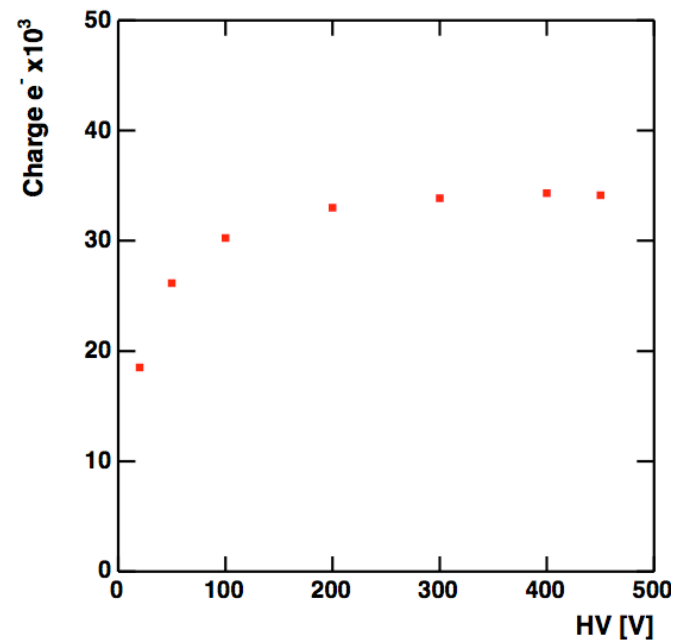
# Gallium Arsenide (7)

- Particle detection:



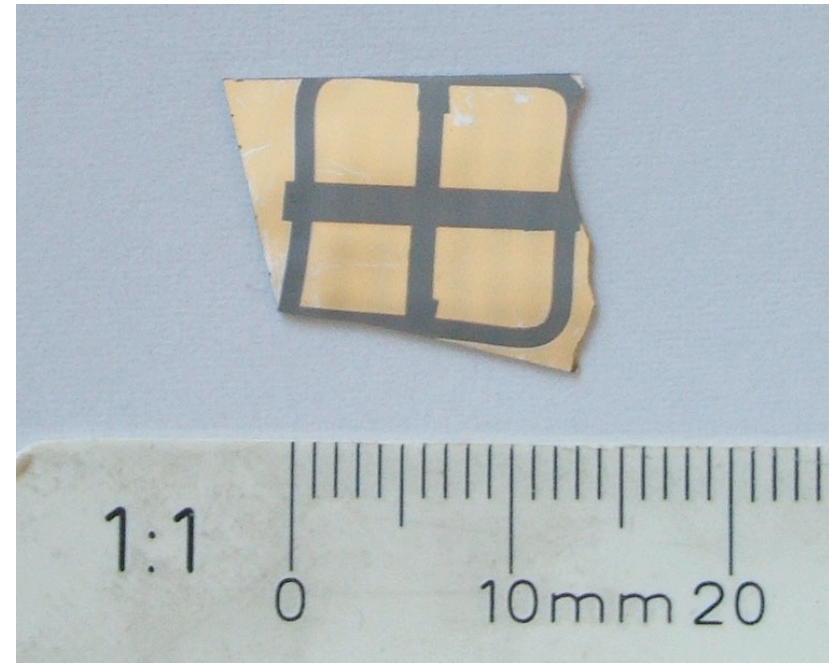
$^{90}\text{Sr}$  spectrum of one pad  
(preliminary)

Courtesy:  
Konstantin Afanaciev



# Silicon Carbide (1)

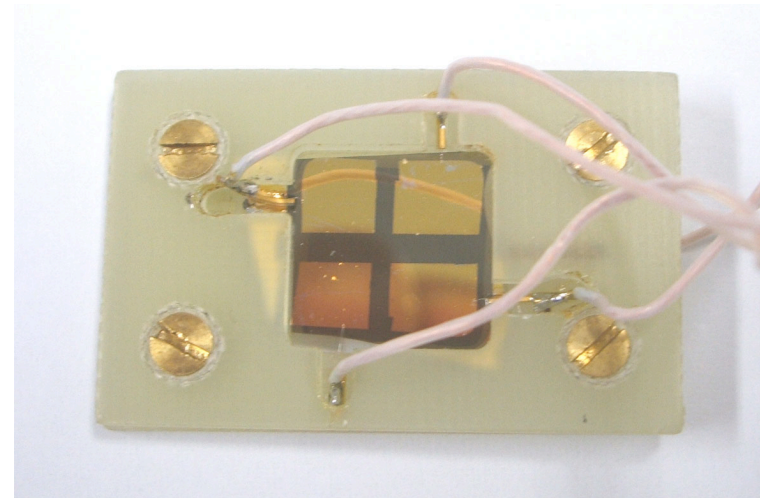
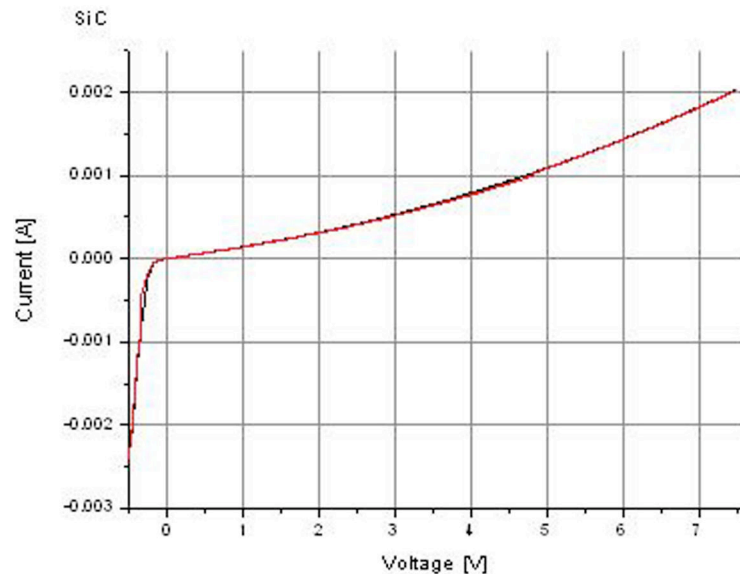
- wide bandgap material:  $\sim (3 \dots 3.35) \text{ eV}$ 
  - > solid state ionization chamber
- normally produced as epi layer (CVD) on silicon (industry!)
- SiC at wafer scale up to 75 mm (3")
- still high defect densities (15 to 30 'micropipes' per  $\text{cm}^2$ )
- cost per  $\text{cm}^2$ : (150 ... 300) Euro
- metal deposition ->
  - Schottky contact
    - > annealing @ high T -> ohmic contacts
- planned collaboration with BTU Cottbus





# Silicon Carbide (2)

- low ohmic material - see I/V curve:



- use for detection of ionizing particles impossible (recombination with leakage current)...



# CONCLUSIONS

- harsh environment (irradiation) demands new detector materials
- current *silicon* does not survive the high rad level
  - test of developed sensors for such high rad levels
  - search for collaborators to share effort and cost
- *GaAs*: growing knowledge and experience (LHC etc)
  - promising detector capabilities
  - samples investigated, measurements to be continued
- *pCVD diamonds* survive high doses
  - current samples are not (long term) stable as detectors
  - recommended only for counting applications (threshold!)
- *Silicon Carbide* is a candidate for radiation hardness
  - we need high ohmic material (difficult to get)
  - first investigated sample impossible to use

